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APPLICANTS

David Berman, Kiryat Tivon, ISRAEL;
 Alex Dikopoltsev, Haifa, ISRAEL;

** CONTINUING DATA *****
 This application is a CIP of 10/300,504 11/20/2002 PAT 6,639,968
 and is a CIP of 10/313,280 12/06/2002 PAT 6,947,520
 and is a CIP of 10/364,883 02/12/2003 PAT 6,895,075
 which is a DIV of 09/833,902 04/12/2001 PAT 6,512,814

OK

** FOREIGN APPLICATIONS ***** None

IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** SMALL ENTITY **
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Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	STATE OR COUNTRY ISRAEL	SHEETS DRAWING 6	TOTAL CLAIMS 48	INDEPENDENT CLAIMS 10
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35 USC 119 (a-d) conditions met ☐ yes ☒ no ☐ Met after Allowance

Verified and Acknowledged
 Examiner's Signature: [Signature] Initials: [Initials]

ADDRESS
 1912
 AMSTER, ROTHSTEIN & EBENSTEIN LLP
 90 PARK AVENUE
 NEW YORK, NY
 10016

TITLE
 X-ray reflectometry of thin film layers with enhanced accuracy

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